

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10824434	YOON ET AL.
Examiner	Art Unit	
Tan, Alvin H	2173	

SEARCHED

Class	Subclass	Date	Examiner
715	744, 747	5/3/07 (Updated 11/20/08)	/AT/ (/AT/)

SEARCH NOTES

Search Notes	Date	Examiner
715/744-747 (text search only - see search history printout)	5/3/07 (Updated 11/20/08)	/AT/ (/AT/)
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, IBM_TDB) - See Search History Printout	5/3/07 (Updated 11/20/08)	/AT/ (/AT/)
NPL - ACM Portal	5/4/07	AT

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner